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EORM PTO 4449	SERIAL NO. 10/035,025	CASE NO. 10544/169
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE December 28, 2001	GROUP ART UNIT 2882
(use several sheets if necessary)	APPLICANT(S): Vladimir V. Pı	rotopov

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	SUBCLASS	DATE
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EMI EMI	A2	3,032,656	05/1/1962	Hosemann et al.		
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ENY.	A14	4,643,951	02/17/1987	Keem et al.		
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EM X	A16	4,684,565	08/04/1987	Abeles et al.		
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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATIONS FOR STATEMENT

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SERIAL NO.

10/035,025

FILING DATE
December 28, 2001

APPLICANT(S): Vladimir V. Protopov

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EM Y	A39	5,245,648	09/14/1993	Kinney et al.		
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P.W.X	A46	5,458,084	10/17/1995	Thorne et al.		
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PMY	A53	5,715,291	02/03/1998	Momose		
END	A54	5,732,120	03/24/1998	Shoji et al.		
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KMB	A74	6,144,719	11/7/2000	Hasegawa et al.		
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FORM PTO-1449	DEC 2 3 2002 H	SERIAL NO.	CASE NO.
	F	10/035,025	10544/169
LIST OF PA	NENTS AND PUBLICATIONS FOR	FILING DATE	GROUP ART UNIT
APPLICAN	T'S PAR TION DISCLOSURE	December 28, 2001	2882
	STATEMENT		
(use several sheets if necessary)		APPLICANT(S): Vladimir V. P	rotopov

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L	INITIAL		NUMBER	DATE	NAME	SUBCLASS	DATE
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STATEMENT		
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INITIAL A98 English language abstract regarding Japanese published application No. 63-53456 that was published March 7, 1988, while the date of publication of the English language abstract is unknown it is believed to have occurred prior to March 1, 2000. A99 English language abstract regarding Japanese published application No. 1-187440 that was published July 26, 1989, while the date of publication of the English language abstract is unknown it is believed to have occurred prior to March 1, 2000. A100 Pending U.S. Patent Application Serial No. 09/797,498, filed March 1, 2001 by Marryhov et al. A101 V.V. Protopopov et al., "X-Ray Mutillayer Mirrors With An Extended Angular Range," Optics Communications, Vol. 158, December 15, 1998, pp. 127-140. A102 V.V. Protopopov, "On the Possibility of X-Ray Refractive Radiography Using Mutilayer Mirrors With Resonant Absorption," Optics Communications, Vol. 174, January 15, 2000, pp. 13-18. A103 Richard Fitzgerald, "Phase-Sensitive X-Ray Imaging," Physics Today, July 2000, pp. 23-26. A104 V.V. Protopopov et al., "Observation of X-Ray Refraction Contrast Using Mutilayer Mirrors With Resonant Absorption," Optics Communications, Dispatch 17, August 2000, pp. 1-6. INSPEC Abstract Number A1999-18-8760J-017, B1999-09-7510P-044, available on or before February 8, 2001, 2 pages, regarding "Mammography Imaging Studies Using A Laue Crystal Analyzer," by Chapman et al., Review of Scientific Instruments Conference, Vol. 67, No. 9, September 1996, p. 5. A107 INSPEC Abstract Number A9514-0785-044, B9508-7450-005, available on or before February 8, 2001, 2 pages, regarding "Backscattering Analyzer Geometry As A Straightforward and Precise Method for Monochromator Characterization at Third-Generation Synchrotron-Radiation Sources," by Snigirev et al., Review of Scientific Instruments, Vol. 68, No. 2, Pt. 2, February, 1995, p. 2228. A107 INSPEC Abstract Number A9510-0785-002, available on or before February 8, 2001, 2 pages, regarding "Polarization Analysis in Magnetic X-Ray Scat	EXAMINER		
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